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[1][2] MEMS

.[3]

.[13]

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1

2

<sup>3</sup> Micro Electronic Mechanical Systems

<sup>4</sup> Etching

John von Neumann

[4][5]

Stanislaw Ulam

 $\phi$ 

V

d

{ $\Sigma, d, V, \phi$ } $k = |\Sigma|$  $\Sigma$ 

2r+1

 $\Sigma = \{0,1\}$  k=2 $\phi = \Sigma^{2^{i+1}} \rightarrow \Sigma$ 

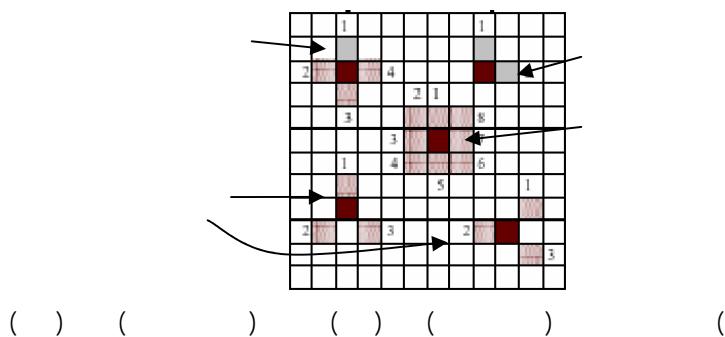
( )

 $\phi$ 

x=1

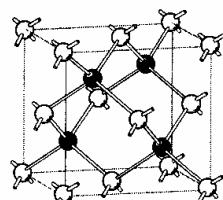
[6]

[7]

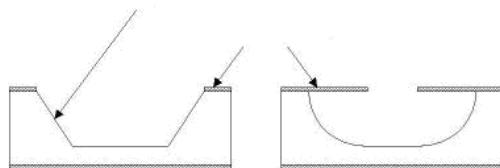



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<sup>1</sup> Line by Line sweep



( )



( )

[9]

( )

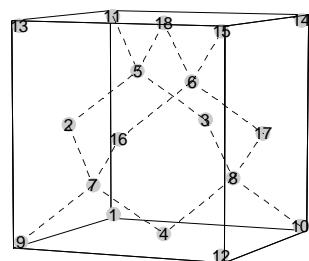
<sup>1</sup> Isotropic  
<sup>2</sup> Anisotropic

(

[10-12]

( )

( )



(

0,0,0	
1,0,0	
-1,0,0	
0,1,0	
0,-1,0	
0,0,1	
0,0,-1	
-1,-1,-1	
1,1,1	

(

0,0,0	
1/2,0,1/2	
0,1/2,1/2	
1/2,1/2,0	
1/4,1/4,3/4	
3/4,3/4,3/4	
3/4,1/4,1/4	
1/4,3/4,1/4	

(

<sup>1</sup> Unit Cell  
<sup>2</sup> Net Atom

( )	( )	( )	( )	
( )	( )			
		( )	( )	
( )	( )			
		( )	( )	
( )	( )	( )	( )	
( )		( )		
		( )	( )	

(

{2,2,2,2,2,2,2}

{2,1,1,2,0,2,2,2}

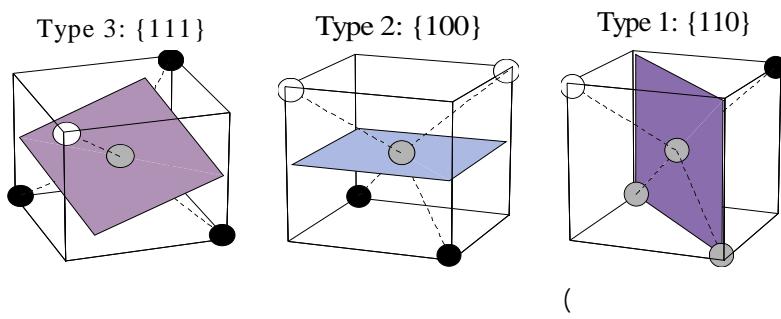

(

{111} {110} {100}

{110} Si

{100} Si

{111} Si



KOH

50:30:1 R<sub>110</sub>:R<sub>100</sub>:R<sub>111</sub>

160:100:1

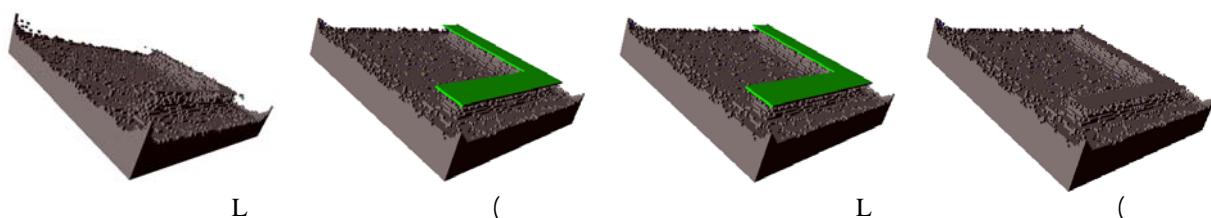
$$P_{hkl} = R_{khl} / (R_{110} + R_{100} + R_{111}) \quad ( )$$

hkl

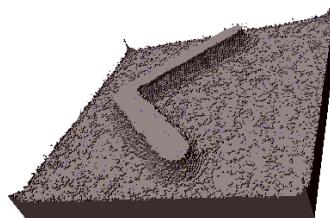
[0,P <sub>100</sub> ]	(0 < RND < 1) RND	Si
[0,P <sub>110</sub> ]	RND	Si
[0,P <sub>111</sub> ]	RND	Si
		Si

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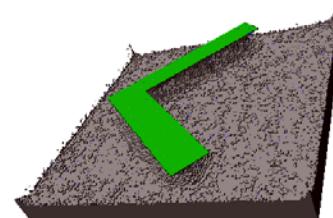
L



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L



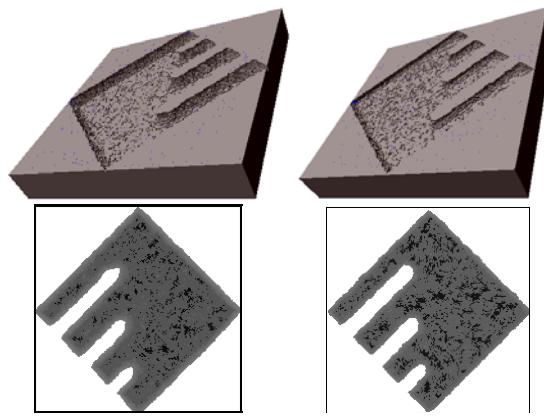
(

{110}

SEM [14]

[14]

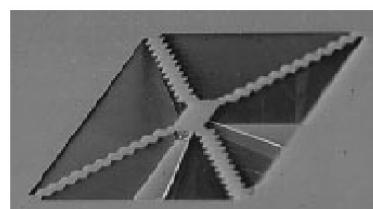
<sup>1</sup> Under-Cutting



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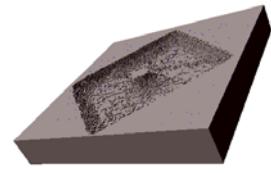
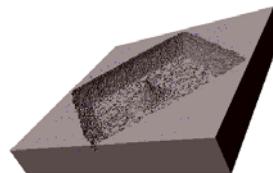
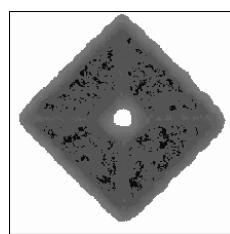
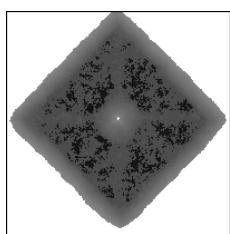
[9]

SEM



SEM

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<sup>1</sup> Cross-Beams

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